Technical Specifications

Specification	SP2000UV	SP4000UV
Optical System	Single Beam	
Light Source	Tungsten / Deuterium	
Spectral Bandwidth	2 nm	
Wavelength Range	190 ~ 1100 nm	
Wavelength Accuracy	±0.5 nm (±0.3 nm @ 656.1 nm)	
Wavelength Repeatability	≤0.3 nm	≤0.2 nm
Wavelength Resolution	0.1 nm	
Wavelength Scanning Speed (max)	10,000 nm/min	10000 nm/min (max 20–4200 nm/min adj.)
Wavelength Scanning Speed (variable)	—	20 ~ 4,200 nm/min
Photometric Range	-0.3~3A, 0~200%T, 0~9999.9C	
Photometric Accuracy	±0.003 A @ 0.0 ~ 0.5 A，±0.006 A @ 0.5 ~ 1 A，±0.5 %T @ 0 ~ 100 %T	±0.002 A @ 0.0 ~ 0.5 A，±0.004 A @ 0.5 ~ 1 A, ±0.5 %T @ 0 ~ 100 %T
Photometric Repeatability	0.002 A @ 0.0 ~ 0.5 A，≤0.003 A @ 0.5 ~ 1 A，≤0.2 %T @ 0 ~ 100 %T	≤0.001 A (0~0.5 A); ≤0.002 A (0.5~1 A); ≤0.2 %T
Photometric Noise	≤0.0001A@500nm RMS	
Baseline Drift	≤0.002 A/h @ 500 nm (2 hrs after preheat)	
Baseline Flatness	—	±0.002 A
Stray Light	≤0.2 %T @ 340 nm (NaNO2); ≤0.05 %T @ 220 nm (Nal)	0.05 %T @ 340 nm (NaNO2); ≤0.05 %T @ 220 nm (Nal)
Measurement Modes	Photometry, Quantitation	Photometry, Quantitation, scanning
Detector	Silicon Photodiode	
Sample Compartment	10 mm 4-cell manual charger	
Display	5" TFT color touchscreen	
Data Storage	236 KB (built-in), unlimited via USB	
Interfaces	RS232 ×1 (printer), USB-A ×1, USB-B ×1 (PC)	
Power Supply	100 ~ 240 V AC, 50/60 Hz, 120 VA	
Dimensions (W×D×H in/mm)	18 x 14 x 17 / 456 x 360 x 185	
Weight (lbs/kg)	23.5 / 10.6	